

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**General Description**

The SRE100N065FSU2DB is a Field Stop Trench IGBT with anti-parallel diode, which offers ultra-low conduction loss, high energy efficiency for switching applications such as Inverter, PFC, Converter, etc.

The SRE100N065FSU2DB package is TO-247.

**Features**

- High Breakdown Voltage to 700V@T<sub>j</sub>=25°C
- Advanced Trench Fieldstop technology
  - Smooth Switching Off with Lower Spike
  - High Ruggedness, Temperature Stability
  - Easy Parallel Switching Capability due to Positive Temperature Coefficient in V<sub>CE(SAT)</sub>
- Low V<sub>CE(SAT)</sub>
- Enhanced Avalanche Capability
- Non-Automotive Qualified

**Application**

- PFC application
- Inverter & Solar
- Converter with high switching frequency

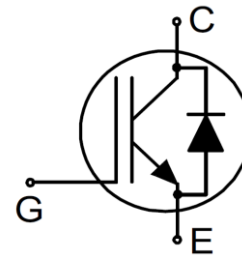
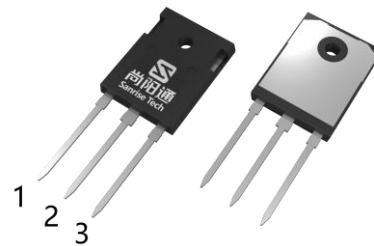
**Symbol**


Figure 1 Symbol of SRE100N065FSU2DB

**Package Type**


TO-247

- Pin 1- Gate
- Pin 2&backside- Collector
- Pin 3- Emitter

Figure 2 Package Type of SRE100N065FSU2DB

**Ordering Information**

SRE100N065FSU2DB □ □ - □

Circuit Type			
Package			E: Lead Free
T: TO-247			Blank: Tube
			TR: Tape & Reel

Package	Part Number	Marking ID	Packing Type
TO-247	SRE100N065FSU2DBT-G2	SRE100N065FSU2DBT-G2	Tube

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Absolute Maximum Ratings**

Parameter		Symbol	Rating	Unit
Collector-emitter voltage		$V_{CES}$	650	V
Gate-emitter Voltage		$V_{GES}$	$\pm 20$	V
Transient Gate-emitter Voltage			$\pm 30$	V
Continuous Collector Current	$T_C=25^\circ\text{C}$	$I_C$	150	A
	$T_C=100^\circ\text{C}$		100	
Pulsed Collector Current, Limited by $T_{Jmax}$		$I_{CM}$	400	A
Diode Continuous Collector Current	$T_C=25^\circ\text{C}$	$I_F$	120	A
	$T_C=100^\circ\text{C}$		100	A
Diode Pulsed Current, Limited by $T_{Jmax}$		$I_{FM}$	320	A
Power Dissipation	$T_C=25^\circ\text{C}$	$P_{tot}$	394	W
	$T_C=100^\circ\text{C}$		197	
Short Circuit withstand time: $V_{GE}=15\text{V}, V_{CC} \leq 400\text{V}, T_{j\_start}=25^\circ\text{C};$ Allow number of short circuits < 1000; Time between short circuits: 1.0S;		tsc	6	us
Operating Junction Temperature Range		$T_J$	$-40 \sim 175^{(1)}$	$^\circ\text{C}$
Storage Temperature		$T_{STG}$	$-55 \sim 150$	$^\circ\text{C}$
Lead Temperature (Soldering, 10 sec)		$T_{LEAD}$	260	$^\circ\text{C}$

Note:

1. Reliability testing conducted at  $T_{Jmax}=175^\circ\text{C}$ .

**Thermal Resistance**

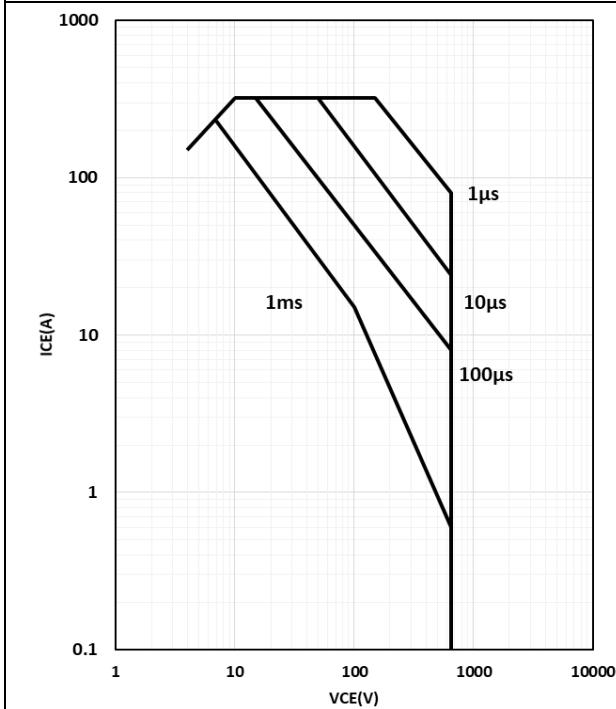
Parameter	Symbol	Min.	Typ.	Max.	Unit
IGBT thermal Resistance, Junction-to-Case	$R_{thJC}$	-	-	0.38	$^\circ\text{C}/\text{W}$
Diode thermal Resistance, Junction-to-Case	$R_{thJC}$	-	-	0.45	
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	-	-	40	

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Electrical Characteristics**
 $T_J = 25^\circ\text{C}$ , unless otherwise specified.

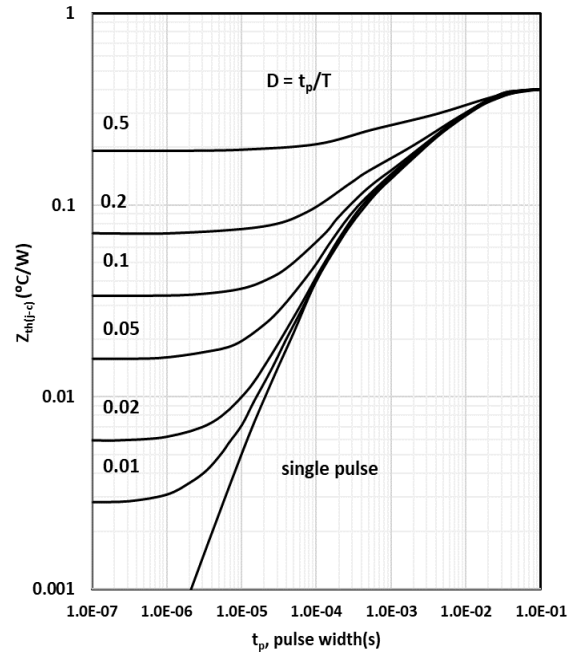
Parameter		Symbol	Test Conditions	Min	Typ	Max	Unit	
<b>Statistic Characteristics</b>								
Collector-emitter Breakdown Voltage		$BV_{CES}$	$V_{GE}=0V, I_C=1mA$	700			V	
Gate Threshold Voltage		$V_{GE(th)}$	$V_{CE}=V_{GE}, I_C=250\mu A$	3.8	4.5	5.4	V	
Collector-emitter saturation voltage		$V_{CEsat}$	$V_{GE}=15V, I_C=100A,$ $T_J=25^\circ\text{C}$		1.57	1.9	V	
			$T_J=125^\circ\text{C}$		1.89		V	
			$T_J=175^\circ\text{C}$		2.08		V	
Zero Gate Voltage Collector Current		$I_{CES}$	$V_{CE}=650V, V_{GE}=0V$ $T_J=25^\circ\text{C}$		0.1	40	$\mu A$	
			$T_J=175^\circ\text{C}$			1	mA	
Gate-emitter Leakage Current	Forward	$I_{GESF}$	$V_{GE}=20V, V_{CE}=0V$			100	nA	
	Reverse	$I_{GESR}$	$V_{GE}=-20V, V_{CE}=0V$			-100	nA	
<b>Dynamic Characteristics</b>								
Input Capacitance		$C_{IES}$	$V_{CE}=25V, V_{GE}=0V,$ $f=1\text{ MHz}$		3750		pF	
Output Capacitance		$C_{OES}$			350			
Reverse Transfer Capacitance		$C_{RES}$			40			
Gate Resistance		$R_G$	$f=1\text{ MHz}, \text{Open Drain}$		1.7		$\Omega$	
Turn-on Delay Time		$t_{d(on)}$	$T_J=25^\circ\text{C}$ $V_{CC}=400V, I_C=100A$ $R_G=10\Omega, V_{GE}=0/15V$ Energy losses include "tail" and diode reverse recovery		67		ns	
Rise Time		$t_r$			96		ns	
Turn-off Delay Time		$t_{d(off)}$			262		ns	
Fall Time		$t_f$			153		ns	
Turn-on energy		$E_{on}$			4.0		mJ	
Turn-off energy		$E_{off}$			1.4		mJ	
Total switching energy		$E_{ts}$			5.4		mJ	
Turn-on Delay Time		$t_{d(on)}$		$T_J=150^\circ\text{C}$ $V_{CC}=400V, I_C=100A$ $R_G=10\Omega, V_{GE}=0/15V$ Energy losses include "tail" and diode reverse recovery		67		ns
Rise Time		$t_r$				114		ns
Turn-off Delay Time		$t_{d(off)}$				289		ns
Fall Time		$t_f$			168		ns	
Turn-on energy		$E_{on}$			4.6		mJ	
Turn-off energy		$E_{off}$			1.8		mJ	
Total switching energy		$E_{ts}$			6.4		mJ	
Gate to Emitter Charge		$Q_{GE}$	$V_{CC}=400V, I_C=100A$ $V_{GE}=0\text{ to }15V$		42		nC	
Gate to Collector Charge		$Q_{GC}$			72			
Gate Charge Total		$Q_G$			162			

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**

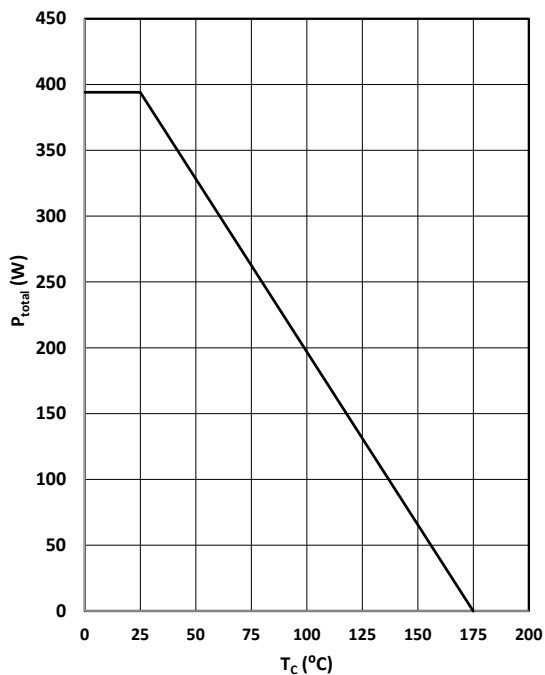
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Reverse Diode Characteristics</b>						
Diode Forward Voltage	$V_F$	$I_F=50A$ $T_J=25^\circ C$		1.39	1.7	V
		$I_F=50A$ $T_J=125^\circ C$		1.23		
		$I_F=50A$ $T_J=175^\circ C$		1.13		
		$I_F=100A$ $T_J=25^\circ C$		1.71	2.0	
		$I_F=100A$ $T_J=125^\circ C$		1.62		
		$I_F=100A$ $T_J=175^\circ C$		1.55		
Reverse Recovery Time	$t_{rr}$	$T_J=25^\circ C$		190		ns
Reverse Recovery Charge	$Q_{rr}$	$V_R=400V, I_F=50A$		1150		nC
Peak Reverse Recovery Current	$I_{rrm}$	$dI_F/dt=840A/\mu s$		18		A
Reverse Recovery Time	$t_{rr}$	$T_J=25^\circ C$		174		ns
Reverse Recovery Charge	$Q_{rr}$	$V_R=400V, I_F=100A$		760		nC
Peak Reverse Recovery Current	$I_{rrm}$	$dI_F/dt=660A/\mu s$		14		A

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Typical Performance Characteristics**
**Figure 3: IGBT forward bias safe operating area (FBSOA)**


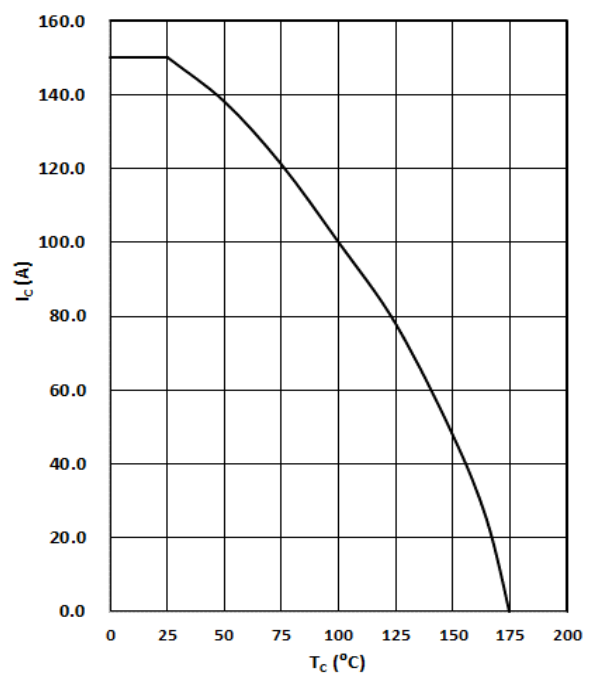
$$I_C = f(V_{CE}); V_{GE} \geq 15/0V; T_j \leq 175^\circ C$$

**Figure 4: IGBT transient thermal impedance**


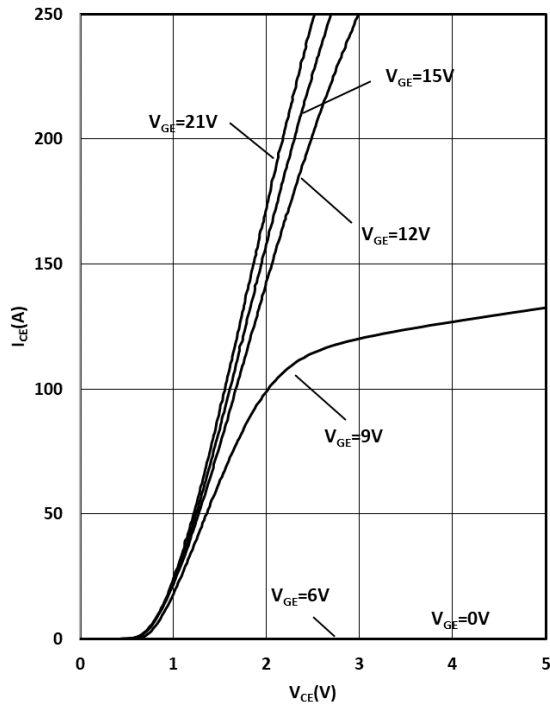
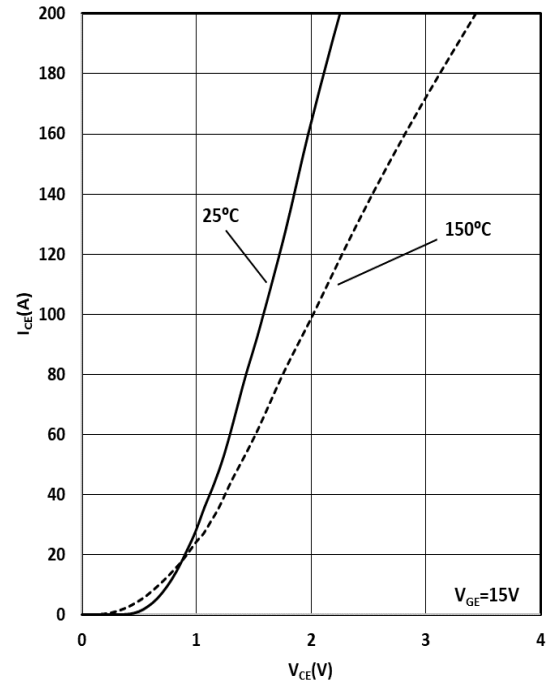
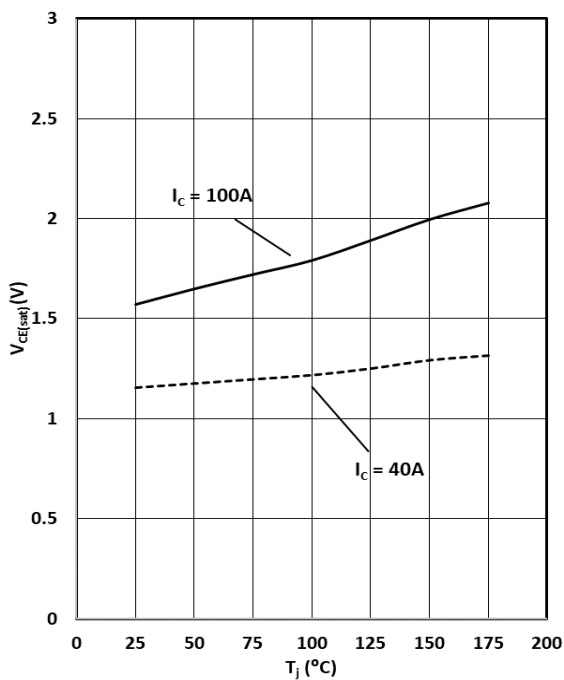
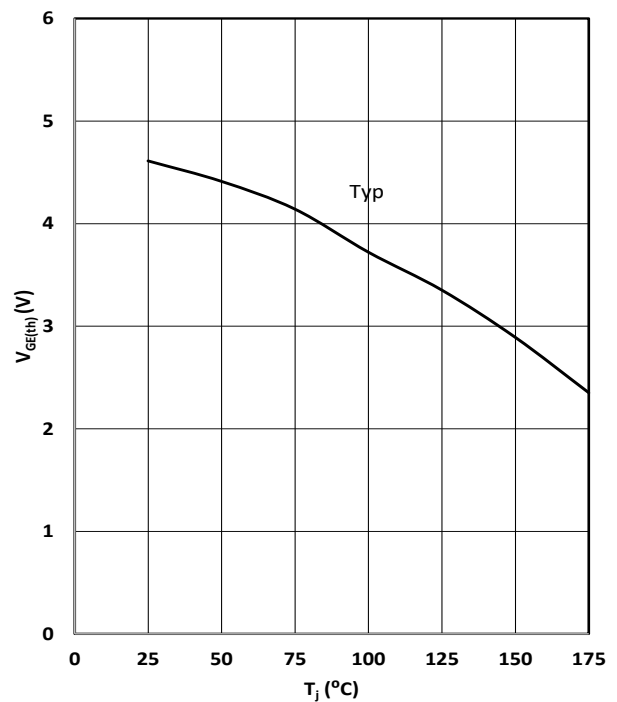
$$R_{th(j-c)} = f(t_p); \text{duty cycle: } D = t_p/T$$

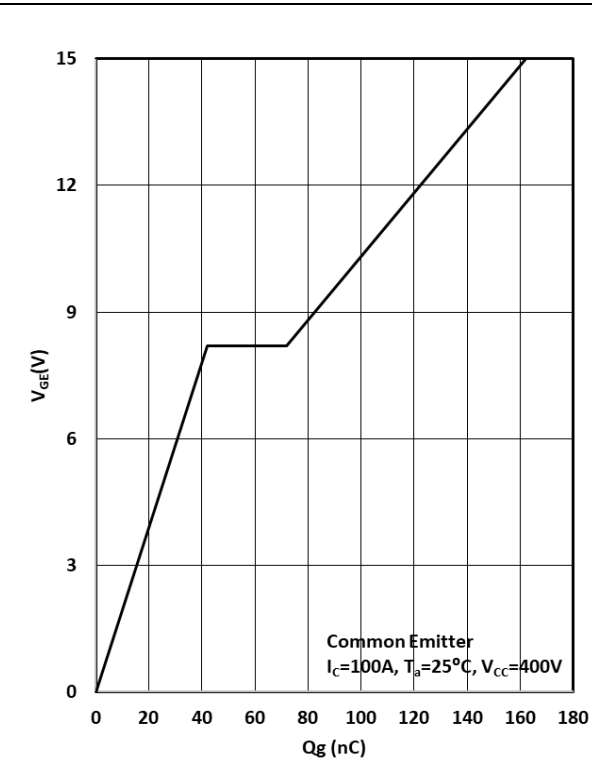
**Figure 5: Power Dissipation**


$$P_{tot} = f(T_c)$$

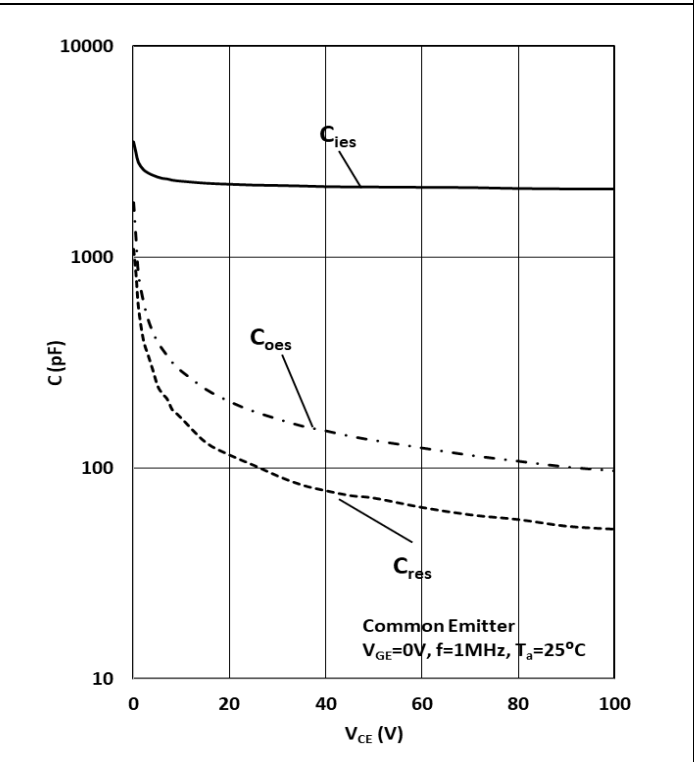
**Figure 6: Collector current vs. temperature**


$$I_C = f(T_j); V_{GE} \geq 15/0V; T_j \leq 175^\circ C$$

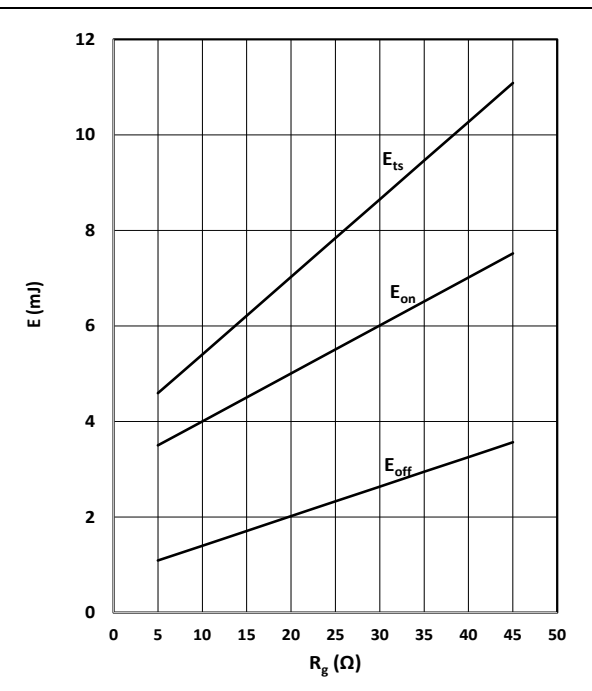
**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Figure 7: Typical Output Characteristics**

 $I_C = f(V_{CE}); T_j = 25^\circ\text{C}; \text{parameter: } V_{GE}$ 
**Figure 8: Typical transfer characteristic**

 $I_C = f(V_{CE}); T_j = 25^\circ\text{C vs } 150^\circ\text{C}; V_{CE} = 15\text{V}$ 
**Figure 9: Typical collector-emitter saturation voltage as a function of junction temperature**

 $V_{CE} = f(T_j); V_{GE} = 15\text{V}$ 
**Figure 10: Gate-emitter threshold voltage as a function of junction temperature**

 $V_{GE} = f(T_j); I_{CE} = 250\mu\text{A}$

**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Figure 11: Typical Gate Charge**


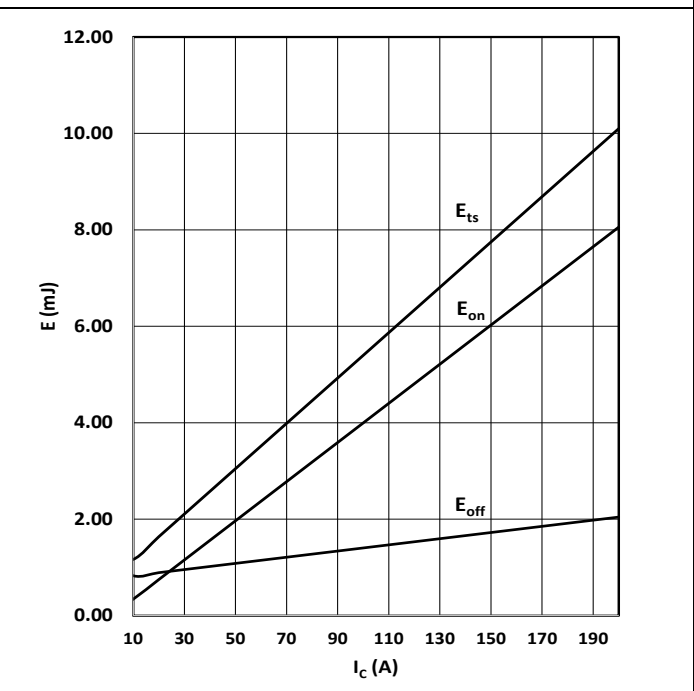
$$V_{GE} = f(Q_{gate}), I_C = 100A$$

**Figure 12: Typical Capacitances**


$$C = f(V_{CE}); V_{GE}=0; f=1MHz$$

**Figure 13: Typical switching energy losses as a function of gate resistor**


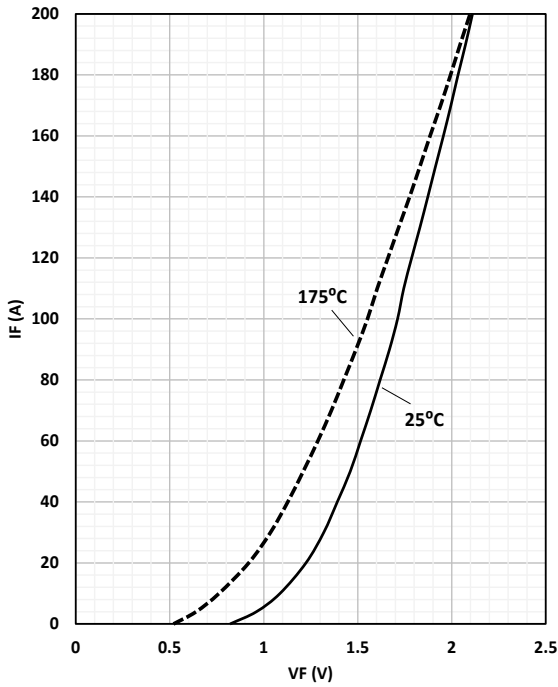
$$E = f(R_G); V_{CE}=400V; T_c=25^\circ C; I_C=100A$$

**Figure 14: Typical switching energy losses as a function of collector current**


$$E = f(I_C); V_{CE}=400V; T_c=25^\circ C; R_G=10\Omega$$

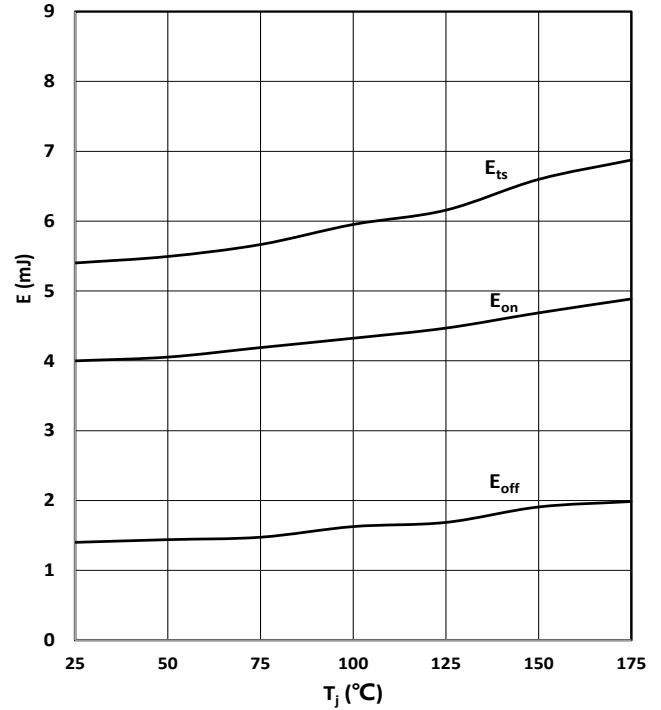
**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**

Figure 15: Typical diode forward current as a function of forward voltage



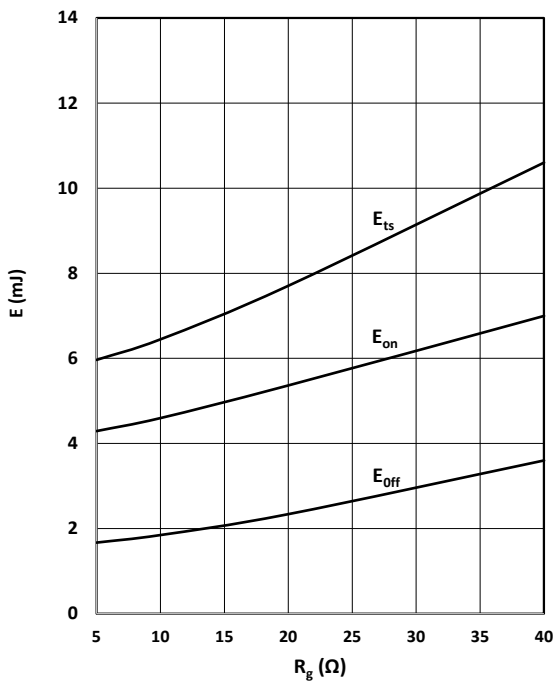
$$I_F = f(V_F);$$

Figure 16: Typical switching energy losses as a function of junction temperature



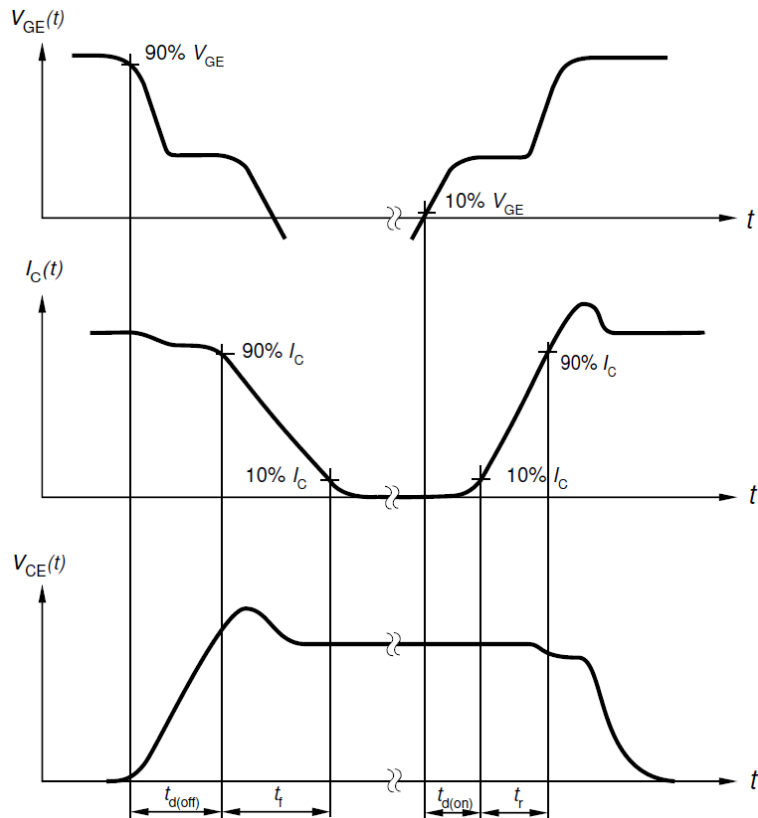
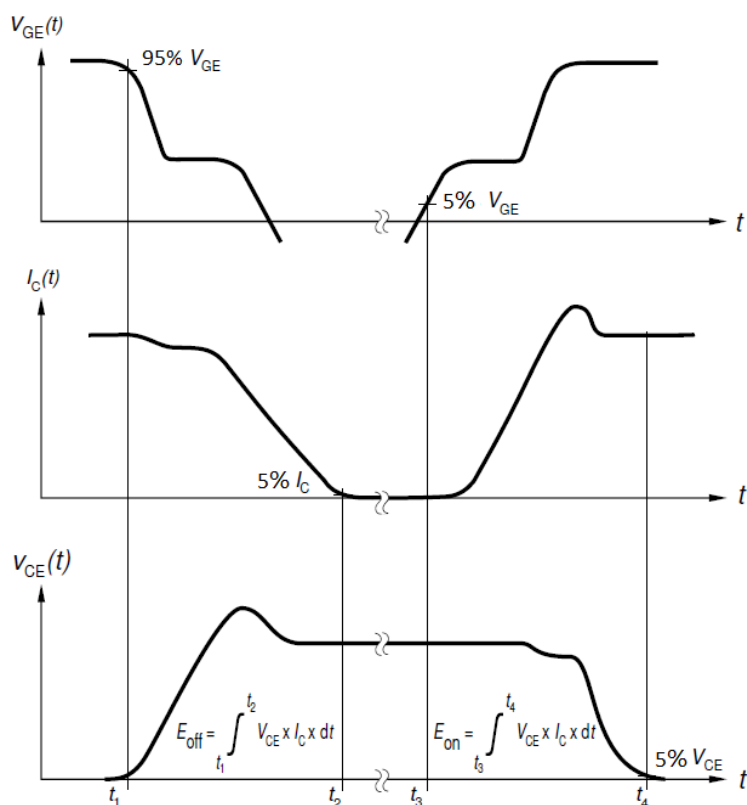
$$E = f(T_j); V_{CE}=400V; I_C=100A; R_G=10\Omega$$

Figure 17: Typical switching energy losses as a function of gate resistor

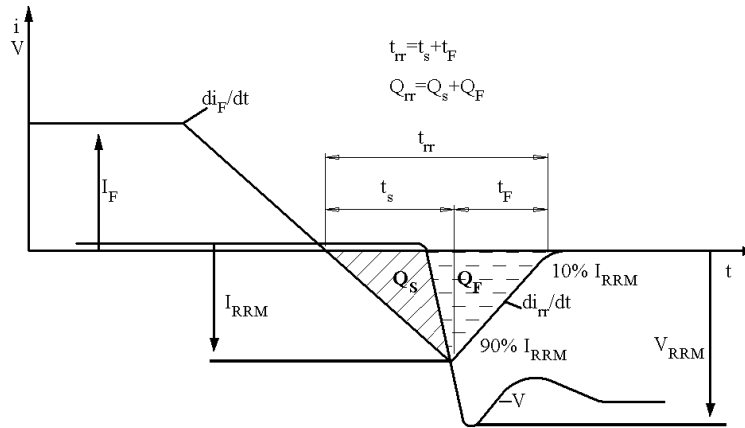


$$E = f(R_G); V_{CE}=400V; T_c=150^\circ C; I_C=100A$$

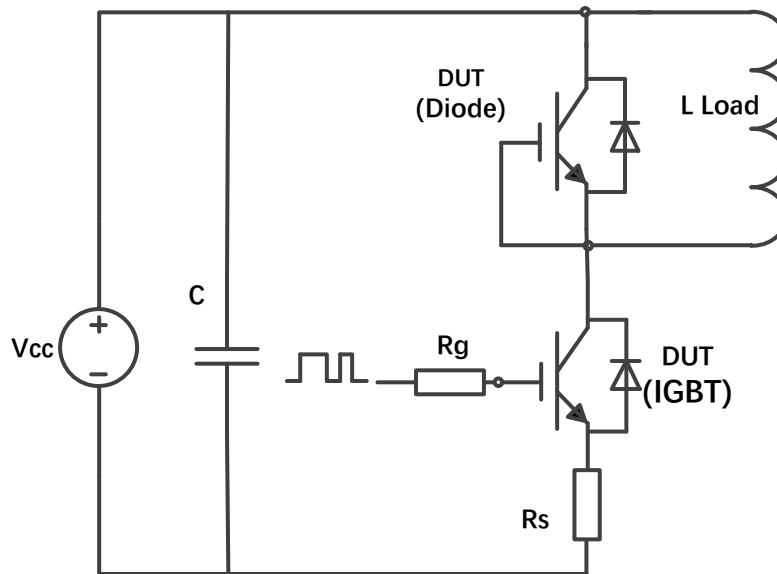


**Test Circuits**
**1. Definition Switching times**

**2. Definition Switching losses**


### 3. Definition Diode Switching Characteristics



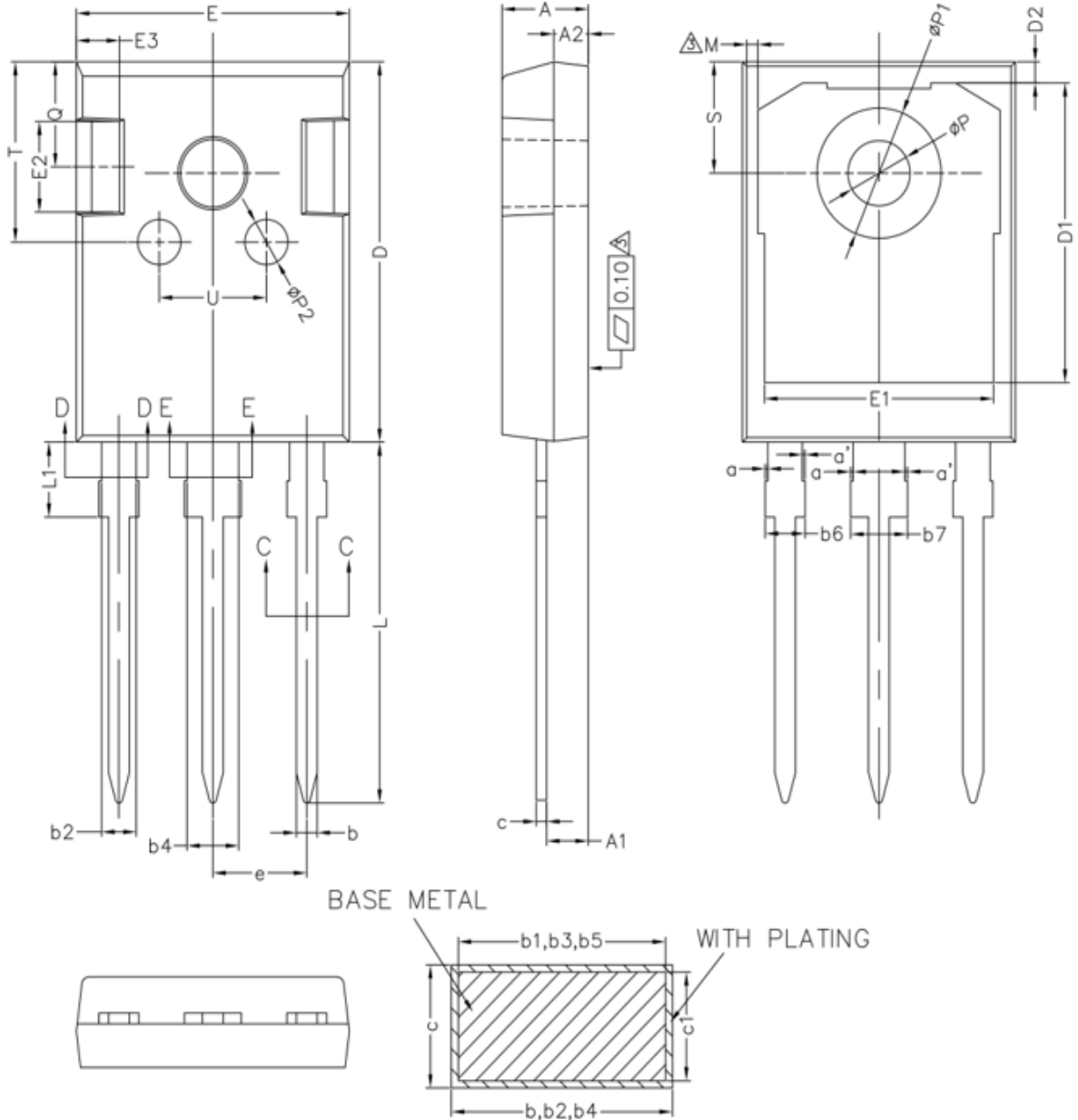
### 4. Dynamic test circuit



**Mechanical Dimensions**

**TO-247**

**Unit: mm**



**100A 650V Trench Fieldstop IGBT with anti-parallel diode SRE100N065FSU2DB**
**Mechanical Dimensions**

Symbol	Dimensions(mm)			Symbol	Dimensions(mm)		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.90	5.00	5.10	D2	1.05	1.20	1.35
A1	2.31	2.41	2.51	E	15.70	15.80	15.90
A2	1.90	2.00	2.10	E1	13.10	13.30	13.50
a	0	-	0.15	E2	4.90	5.00	5.10
a'	0	-	0.15	E3	2.40	2.50	2.60
b	1.16	-	1.26	e	5.34	5.44	5.54
b1	1.15	1.2	1.22	L	19.80	19.92	20.10
b2	1.96	-	2.06	L1	-	-	4.30
b3	1.95	2.00	2.02	M	0.35	-	0.95
b4	2.96	-	3.06	P	3.50	3.60	3.70
b5	2.95	3.00	3.02	P1	7.00	-	7.40
b6	-	-	2.25	P2	2.40	2.50	2.60
b7	-	-	3.25	Q	5.60	-	6.00
c	0.59	-	0.66	S	6.05	6.15	6.25
c1	0.58	0.60	0.62	T	9.80	-	10.20
D	20.90	21.00	21.10	U	6.00	-	6.40
D1	16.25	16.55	16.85	-	-	-	-



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#### **Main Site:**

##### **- Headquarter**

Shenzhen Sanrise Technology Co., LTD.  
A1206, Skyworth building, No. 008, gaoxinnan 1st Road,  
Gaoxin District, Yuehai street, Nanshan District, ShenZhen,  
P.R. China

Tel: +86-755-22953335

Fax: +86-755-22916878

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##### **- Shanghai Office**

Shenzhen Sanrise Technology Co., LTD.  
Rm.401, Building B, No. 666, Zhangheng Road,  
Zhangjiang Hi-Tech Park, Shanghai, P.R.China

Tel: +86-21-68825918

[www.sanrise-tech.com](http://www.sanrise-tech.com)

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